Welcome to another exciting Test Week™ and the 1997 International Test Conference. Now in its 28th year, ITC continues its tradition as the premier annual forum for technical presentations and interactive exchange of ideas with test professionals from around the world. ITC also provides an unmatched opportunity to explore the dynamics of the electronic test industry with its exhibits and product demonstrations from the world’s most technically advanced suppliers of design and test equipment.

ITC’s Test Week 1997 opens with the popular two-day series of tutorials. Many of the traditional tutorials are still available, and we have also introduced several new tutorials on device diagnostics, practical chip-level test engineering, and board-level test engineering. The popular Exhibitors Forum provides insight into product demonstrations and can help organize your visit to the Exhibit floor.

On Monday, ITC’s technical program begins with a plenary session which features a timely address on the future management of the semiconductor manufacturing process by keynote speaker Jim Healy who is the CEO of Genus Corporation. Colin Maunder of British Telecom will then discuss the ramifications of “Plug and Play.” Colin has an international reputation for his technical efforts as co-chair of the ANSI/IEEE 1149.1 standards committee.

After the plenary session, we invite you to attend the exhibit hall opening, which includes an outstanding exhibition of leading edge software and hardware featuring more than 120 companies exhibiting the most advanced electronic products and software in the test industry.

The technical program consists of 41 technical sessions featuring 121 world-class papers. The program features two high-pedigree sessions from manufacturers of today’s most advanced microprocessors, a session to bring you up to date on IEEE test-related standards, a session featuring on-line test, and an unusual session on probe technology, which highlights hot topics from the 1997 SouthWest Test Workshop.

We are also continuing the popular one-day seminar on a special theme. This year’s subject is Mixed-Signal Test, which is continuing to evolve as a very complex and relevant topic. The seminar feature a panel and five special sessions that include 13 papers.

The popular Lecture Series is designed to present pragmatic “how-to” solutions to current test problems for immediate use by test engineers operating in the trenches. This year’s program features Unpowered Opens on Boards plus an in-depth study of Diagnosis and Failure Analysis.

Panel sessions are a traditional ITC highlight and provide an opportunity to interact with the experts. Twelve panel sessions consider the relevance of partial scan, latest results of the Sematech test methods experiment, value of optical test methods, and the impact of contract board manufacturing on test requirements.

Test Week concludes with three one-day hot-topic Workshops on Test Economics, IDDQ Test, and Embedded Core Test.

On behalf of ITC’s many volunteers, staff, and presenters, we welcome you to Washington, D.C. and to the 1997 International Test Conference. It is our pleasure to provide this forum for you, and we sincerely hope that you will benefit from and enjoy the Test Week activities. Before you leave, please complete our evaluation survey—it is our ultimate goal to meet your needs, so please let us hear from you.

Bill Bruce  Ben Bennetts
General Chair  Program Chair